

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/648,271	ESTAKHRI ET AL.	
Examiner	Art Unit	
Denise Tran	2185	

SEARCHED				
Subclass	Date	Examiner		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (USPAT USPUB, EPOAB, JPOAB, DERWENT, IBMTDB)	11/26/05	DT		
inventor Name search (palm and East)	11/26/2005	DT		
711/103,202-203,209, 221; 365/185.33,94 230.03,185.09, 230.09 (text search only search history printouts)	11/26/2005	DT		
714/6,746, 766, 768 (text search only search history printouts)	11/26/2005	DT		